

ON Semiconductor®

ISL9V3040D3S / ISL9V3040S3S / ISL9V3040P3 / ISL9V3040S3

EcoSPARK® 300mJ, 400V, N-Channel Ignition IGBT

General Description

The ISL9V3040D3S, ISL9V3040S3S, ISL9V3040P3, and ISL9V3040S3 are the next generation ignition IGBTs that offer outstanding SCIS capability in the space saving D-Pak (TO-252), as well as the industry standard D²-Pak (TO-263), and TO-262 and TO-220 plastic packages. This device is intended for use in automotive ignition circuits, specifically as a coil driver. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest On Semiconductor sales office for more information.

Formerly Developmental Type 49362

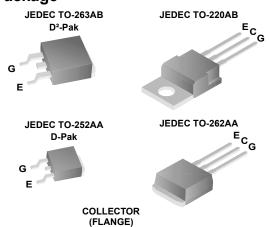
Applications

- · Automotive Ignition Coil Driver Circuits
- · Coil- On Plug Applications

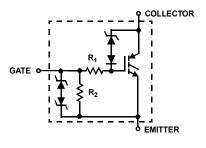
Features

- · Space saving D-Pak package availability
- SCIS Energy = 300mJ at T_J = 25°C
- · Logic Level Gate Drive

Package



Symbol



Device Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	430		
BV _{ECS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V	
E _{SCIS25}	At Starting T _J = 25°C, I _{SCIS} = 14.2A, L = 3.0 mHy	300	mJ	
E _{SCIS150}	At Starting T _J = 150°C, I _{SCIS} = 10.6A, L = 3.0 mHy	170	mJ	
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	21	Α	
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	17	Α	
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V	
P _D	Power Dissipation Total T _C = 25°C	150	W	
	Power Dissipation Derating T _C > 25°C	1.0	W/°C	
TJ	Operating Junction Temperature Range	-40 to 175	°C	
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C	
TL	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C	
T _{pkg}	Max Lead Temp for Soldering (Package Body for 10s)	260	°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω	4	kV	

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Device Marking Device F		Package Reel Size		Tape Width		Quantity				
V3040D		ISL9V3040D3ST		D-252AA	330mm		16mm		2500	
V3040S		ISL9V3040S3ST	T	D-263AB	330mm		24mm		800	
V3040P		ISL9V3040P3		D-220AB		Tube	N/A		50	
V3040S		ISL9V3040S3		D-262AA	Tube		N/A		50	
V3040D		ISL9V3040D3S		D-252AA	Tube		N/A		75	
V304		ISL9V3040S3S	TO-263AB				N/A		50	
		racteristics T _A = 25	l		e no					
Symbol		Parameter		Test Conditions			Min	Тур	Max	Units
off State	Charact	eristics								
BV _{CER}	Collector	Collector to Emitter Breakdown Voltage			$I_C = 2\text{mA}, V_{GE} = 0,$ $R_G = 1\text{K}\Omega$, See Fig. 15 $T_A = -40 \text{ to } 150^{\circ}\text{C}$			400	430	V
BV _{CES}	Collector	Collector to Emitter Breakdown Voltage			I _C = 10mA, V _{GE} = 0, R _G = 0, See Fig. 15 T _J = -40 to 150°C			420	450	V
BV _{ECS}	Emitter t	Emitter to Collector Breakdown Voltage		$I_C = -75 \text{mA}, V_{GE} = 0 \text{V},$ $T_C = 25 ^{\circ} \text{C}$			30	-	-	V
BV_{GES}	Gate to I	Emitter Breakdown Voltage)	$I_{GES} = \pm 2mA$		±12	±14	-	V	
I _{CER}	Collector to Emitter Leakage Current			V _{CER} = 250		T _C = 25°C	-	-	25	μA
	·			R_G = 1KΩ, See Fig. 11		T _C = 150°C	-	-	1	mA
I _{ECS}	Emitter to Collector Leakage Current			V _{EC} = 24V, See Fig. 11		T _C = 25°C	-	-	1	mA
						T _C = 150°C	-	-	40	mA
R ₁	Series Gate Resistance						-	70	-	Ω
R ₂ Gate to Emitter Resistance							10K	-	26K	Ω
n State	Charact	eristics				•				
V _{CE(SAT)}	Collector	ctor to Emitter Saturation Voltage				C = 25°C, See Fig. 3	-	1.25	1.60	V
V _{CE(SAT)}	Collector	ector to Emitter Saturation Voltage				_C = 150°C, See Fig. 4	-	1.58	1.80	V
V _{CE(SAT)}	Collector	Collector to Emitter Saturation Voltage		I _C = 15A, V _{GE} = 4.5V		_C = 150°C	-	1.90	2.20	V
ynamic	Charact	eristics				•				
Q _{G(ON)}	Gate Ch	arge		I _C = 10A, V _{CE} = 12V, V _{GE} = 5V, See Fig. 14		-	17	-	nC	
V _{GE(TH)}	Gate to	Emitter Threshold Voltage		$I_C = 1.0 \text{mA},$		Г _С = 25°С	1.3	-	2.2	V
				V _{CE} = V _{GE,} See Fig. 10	ī	T _C = 150°C	0.75	-	1.8	V
V_{GEP}	Gate to	Emitter Plateau Voltage		$I_C = 10A, V_C$)E =	12V	-	3.0	-	V
witching	Charac	cteristics								
t _{d(ON)R}	Current	Turn-On Delay Time-Resis	tive	V _{CE} = 14V, F	$R_{L} = 1\Omega$		-	0.7	4	μs
t _{rR}	-	Rise Time-Resistive		V _{GE} = 5V, R			-	2.1	7	μs
117	San Sin Nos Timo Nosidivo			T _J = 25°C, See Fig. 12						F- 2
t _{d(OFF)L}	Current	Turn-Off Delay Time-Induc	tive		′, L = 500µHy,		_	4.8	15	μs
t _{fL}	Current	Fall Time-Inductive		V_{GE} = 5V, R_G = 1K Ω T _J = 25°C, See Fig. 12		-	2.8	15	μs	
SCIS	Self Cla	Self Clamped Inductive Switching			T_J = 25°C, L = 3.0 mHy, R_G = 1K Ω , V_{GE} = 5V, See Fig. 1 & 2			-	300	mJ
hermal C	Characte	eristics								
		Resistance Junction-Case		All packages				,	1	°C/V

Typical Performance Curves

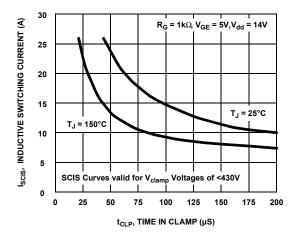


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

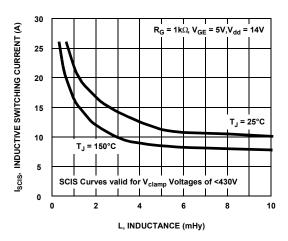


Figure 2. Self Clamped Inductive Switching Current vs Inductance

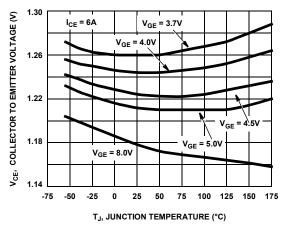


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

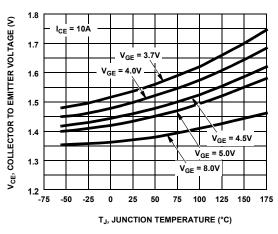


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

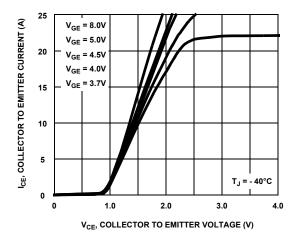


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

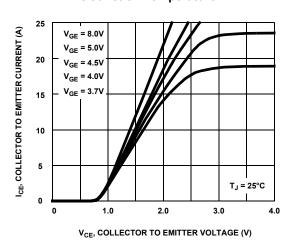
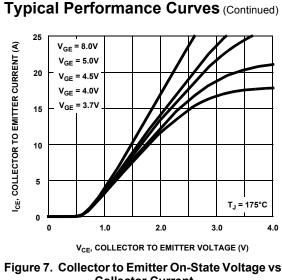


Figure 6. Collector to Emitter On-State Voltage vs Collector Current



Collector Current

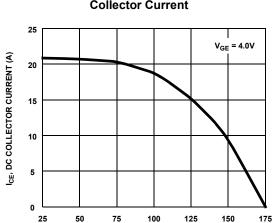


Figure 9. DC Collector Current vs Case **Temperature**

T_C, CASE TEMPERATURE (°C)

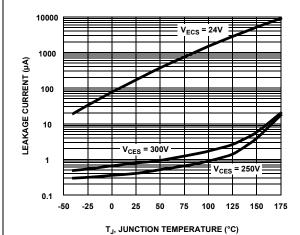


Figure 11. Leakage Current vs Junction Temperature

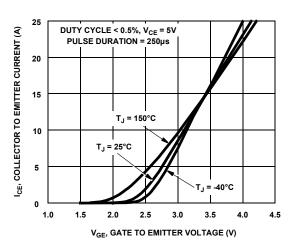


Figure 8. Transfer Characteristics

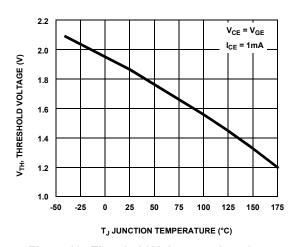


Figure 10. Threshold Voltage vs Junction **Temperature**

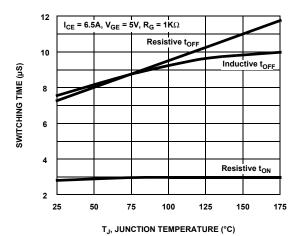
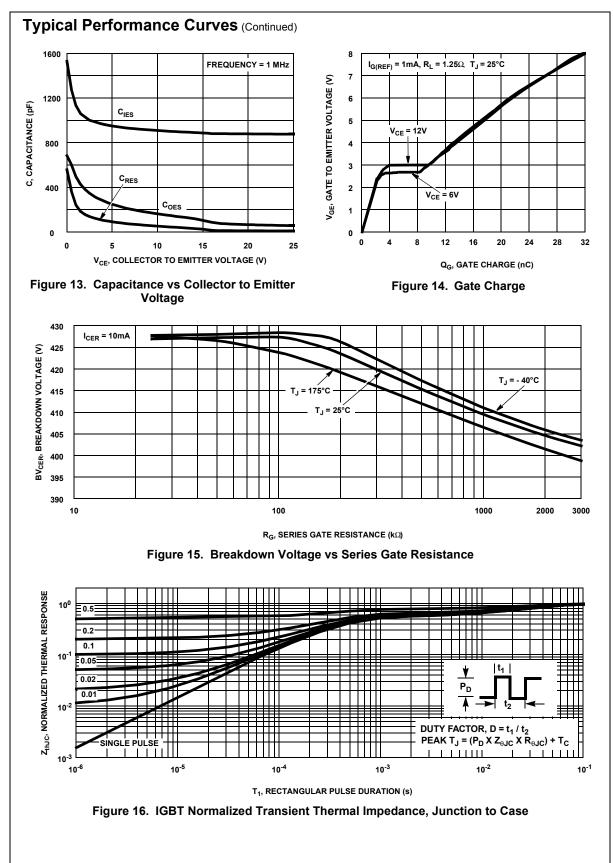
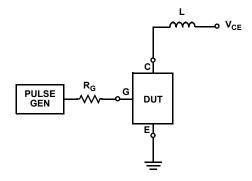


Figure 12. Switching Time vs Junction **Temperature**



Test Circuit and Waveforms



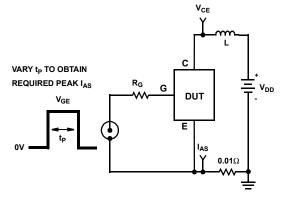
 $R_{G} = 1K\Omega$ 5V E V_{CE}

LOAD

Figure 17. Inductive Switching Test Circuit

Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

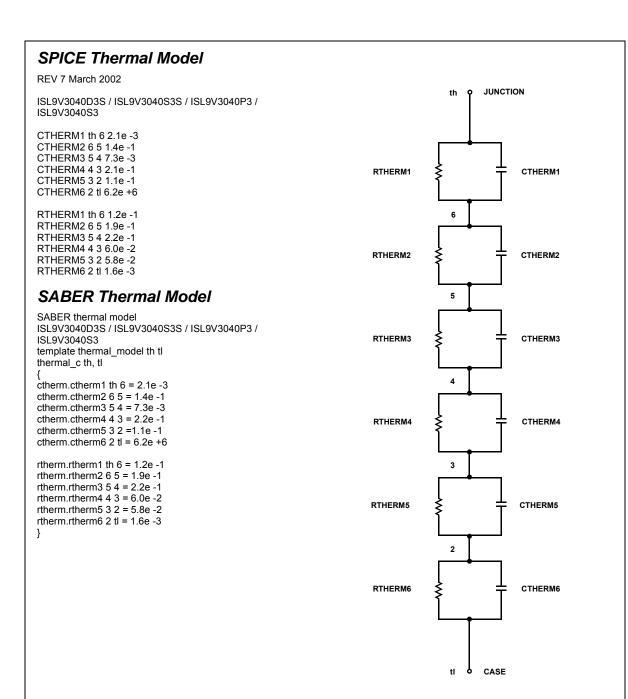
BV_{CES}



V_{DD}

Figure 19. Energy Test Circuit

Figure 20. Energy Waveforms



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